P-587 6-Axis Precision Piezo Stage

Long Scanning Range, Direct Position Measurement

P-587 piezo-driven parallel-kinematics nanopositioning / scanning stage with E-710.6CD 6-axis digital controller

- **For Surface Metrology, Scanning and Positioning in all Six Degrees of Freedom**
- **800 x 800 x 200 µm Linear Range**
- **Up to 1 mrad Rotational Range**
- **Parallel-Kinematics / Metrology for Enhanced Responsiveness / Multi-Axis Precision**
- **Direct Metrology with Capacitive Sensors for Highest Linearity**
- **Outstanding Lifetime Due to PICMA® Piezo Actuators**
- **Frictionless, High-Precision Flexure Guiding System**
- **Active Trajectory Control in All 6 Degrees of Freedom**

The P-587.6CD is a unique, highly accurate, 6-axis scanning and positioning system based on piezo flexure drives. It provides a linear travel range of 800 x 800 x 200 µm and rotation ranges up to 1 mrad.

Application Examples

- Interferometry
- Metrology
- Nano-imprinting
- Semiconductor testing
- Semiconductor fabrication

Direct Position Measurement with Sub-Nanometer Accuracy

PI's proprietary capacitive sensors measure position directly and without physical contact. They are free of friction and hysteresis, a fact which, in combination with the positioning resolution of well under 1 nm, makes it possible to achieve very high levels of linearity. A further advantage of direct metrology with capacitive sensors is the high phase fidelity and the high bandwidth of up to 10 kHz.

Excellent Guiding Accuracy

Flexures optimized with Finite Element Analysis (FEA) are used to guide the stage. FEA techniques are used to give the design the highest possible stiffness in, and perpendicular to, the direction of motion, and to minimize linear and angular runout. Flexures allow extremely high-precision motion, no matter how minute, as they are completely free of play and friction. A flatness and straightness in the low nanometer range is achieved, important for surface metrology applications.

Parallel Kinematics and Metrology with Capacitive Sensors for High Trajectory Fidelity

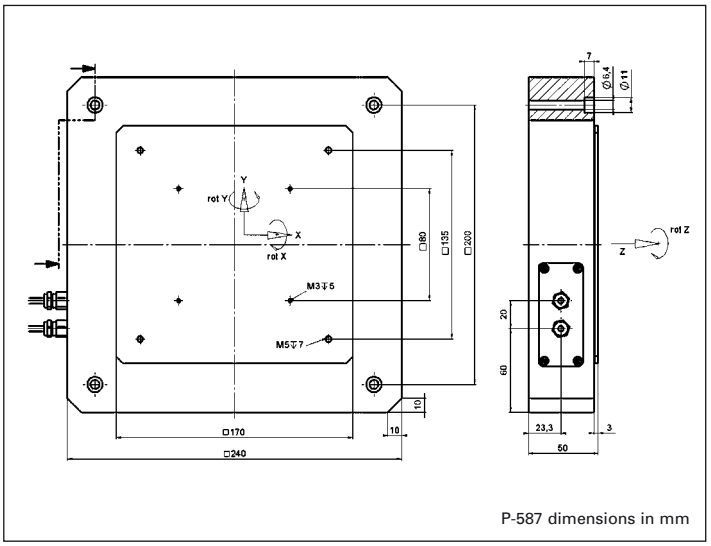
In a parallel kinematics multi-axis system, all actuators act directly on one moving platform. This means that all axes move the same minimized mass and can be designed with identical dynamic properties. Parallel kinematics systems have additional advantages over serially stacked systems, including more-compact construction and no cumulative errors from the individual axes. Multiaxis nanopositioning systems equipped with direct metrology are able to measure platform position in all degrees of freedom against one common reference. In such systems, undesirable motion from one actuator in the direction of another (cross-talk) is detected immediately and actively compensated by the servo-loops. This Active Trajectory Control Concept can keep deviation from a trajectory to under a few nanometers, even in dynamic operation.

Automatic Configuration

PI digital piezo controllers and nanopositioning stages with ID-Chip can be operated in any combination, supported by the AutoCalibration function of the controller. Individual stage data and optimized servo-control parameters are stored in the ID-Chip and are read out automatically by the digital controllers.

Ordering Information

P-587.6CD
6-Axis Nanopositioning System with Long Travel Range, 800 x 800 x 200 µm, ±0.5 mrad, Parallel Metrology, Capacitive Sensors



P-587 dimensions in mm

Technical Data

Model	P-587.6CD	Tolerance
Active axes	X, Y, Z, θ_X, θ_Y, θ_Z	
Motion and positioning		
Integrated sensor	Capacitive	
Closed-loop travel X, Y	800 µm	
Closed-loop travel Z	200 µm	
Closed-loop tip/tilt angle	±0.5 mrad	
Closed-loop θZ angle	±0.5 mrad	
Open-loop / closed-loop resolution X, Y	0.9 / 2.2 nm	typ.
Open-loop / closed-loop resolution Z	0.4 / 0.7 nm	typ.
Open-loop / closed-loop resolution θ_X, θ_Y	0.05 / 0.1 µrad	typ.
Open-loop / closed-loop resolution θ_Z	0.1 / 0.3 µrad	typ.
Linearity X, Y, Z	0.01 %	typ.
Linearity θ_X, θ_Y, θ_Z	0.1 %	typ.
Repeatability X, Y	±3 nm	typ.
Repeatability	±2 nm	typ.
Repeatability θ_X, θ_Y	±0.1 µrad	typ.
Repeatability θ_Z	±0.15 µrad	typ.
Flatness	<15 nm	typ.
Mechanical properties		
Stiffness X / Y / Z	0.55 / 0.55 / 1.35 N/µm	
Unloaded resonant frequency in X / Y / Z	103 / 103 / 235 Hz	±20 %
Resonant frequency @ 500 g in X / Y / Z	88 / 88 / 175 Hz	±20 %
Resonant frequency @ 2000 g in X / Y / Z	65 / 65 / 118 Hz	±20 %
Push/pull force capacity in motion direction	50 / 10 N	Max.
Drive properties		
Ceramic type	PICMA®	
Electrical capacitance in X / Y / Z	81 / 81 / 18.4 µF	±20 %
Dynamic operating current coefficient (DOCC) in X, Y, θ_Z	12.6 µA/(Hz • µm)	±20 %
Dynamic operating current coefficient (DOCC) Z, θ_X, θ_Y	11.5 µA/(Hz • µm)	±20 %
Miscellaneous		
Operating temperature range	-20 to 80 °C	
Material	Aluminum	
Dimensions	240 x 240 x 50 mm	
Mass	7.2 kg	±5 %
Cable length	1.5 m	±10 mm
Sensor / voltage connection	2 x Sub-D Special	
Recommended controller / amplifier	E-710.6CD (p. 2-128) or E-712.6CD (p. 2-140) digital controller	

The maximum rotational angle in θ_Z is 8 mrad, the tilt angles around X and Y rate 3 mrad.
Due to parallel kinematics linear motion is not possible when the stage is in extreme position.